

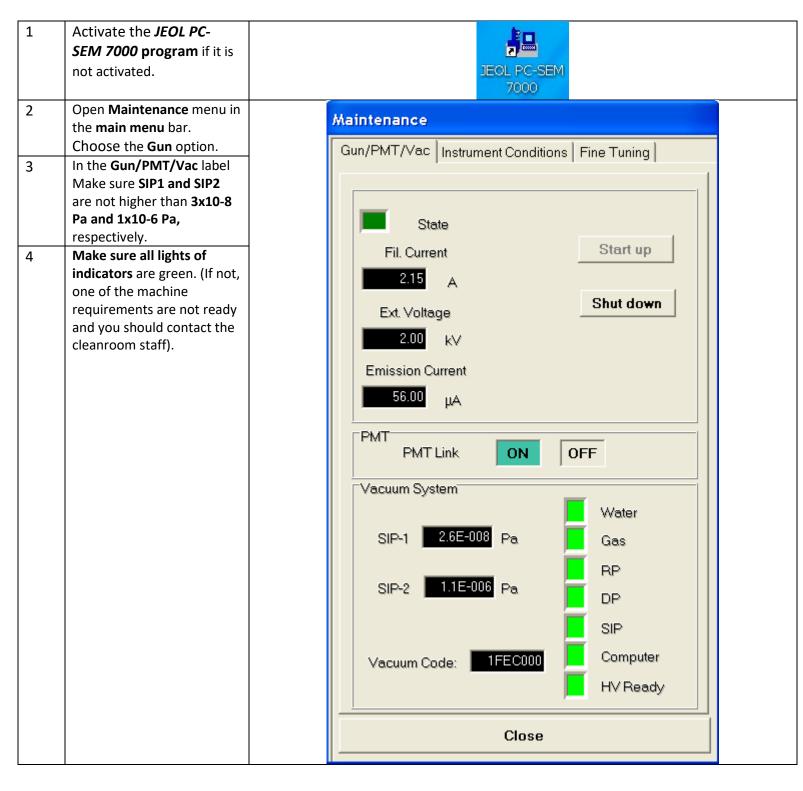
WEIZMANN
INSTITUTE
OF SCIENCE

JEOL 7000F SCAN ELECTRON MICROSCOPE



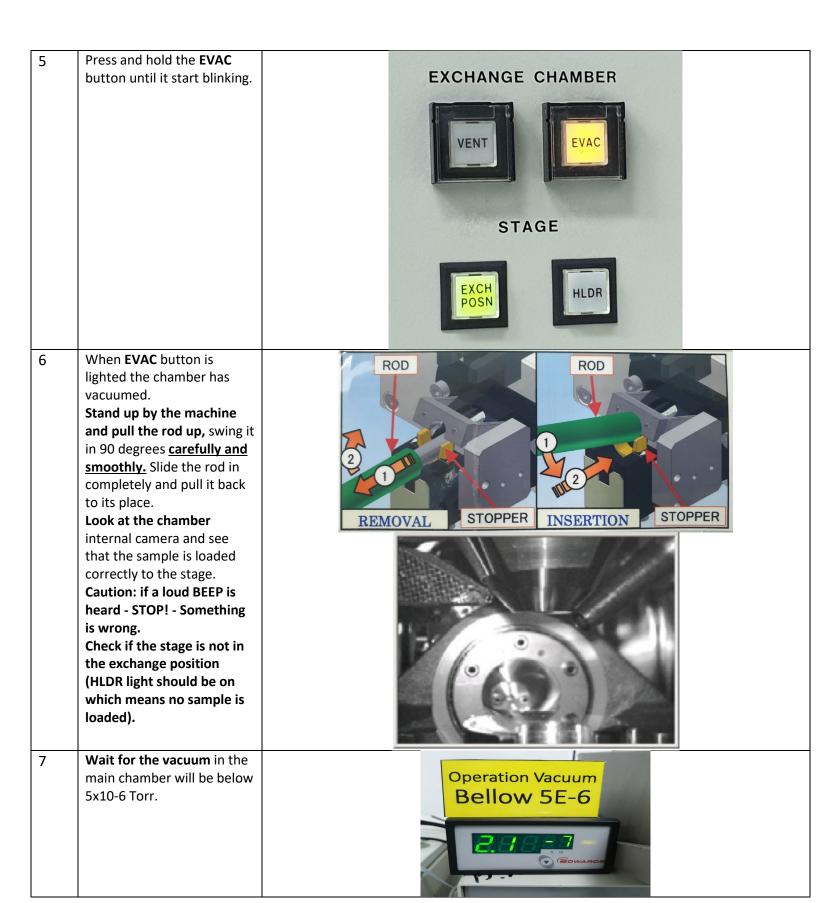


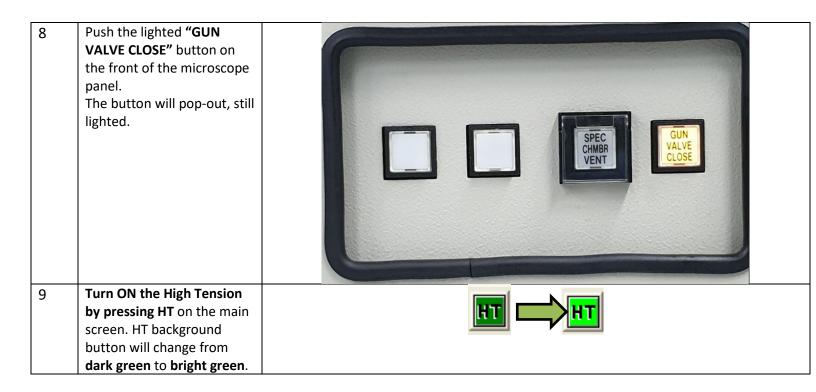
Machine availability check



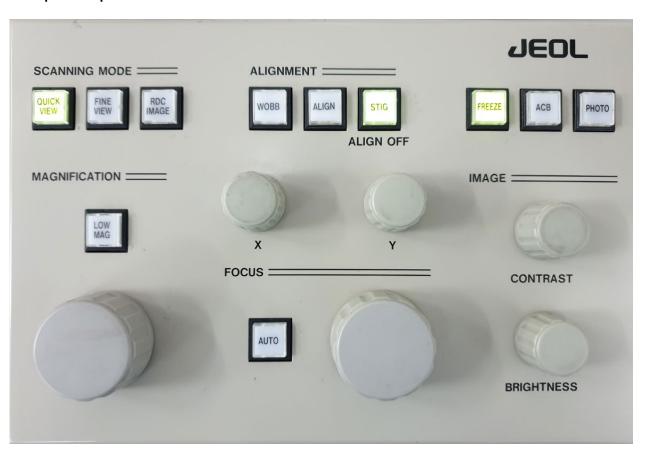
Sample mounting

2	Make sure the HLDR-OFF button is OFF (if there is a specimen in the chamber it will be lighted). Loosen the clip on the side of the exchange chamber. Press and hold the VENT button until it start to blink.	STAGE EXCHANGE CHAMBER VENT
3	When VENT button is lighted the chamber has vented. Open the door and mount the sample holder (the arrows on the sample holder should be parallel to the load lock rail).	Front ROD A CAUTIO REMOVAL J Pull the rod out until the sa cleus Alterwards, lift the rod down up get Insert the rod. Consertion J Conting peak to rod down up get Insert the rod.
4	Check that the O-ring around the door is in the right place. Close the door and shut the loadlock clip.	

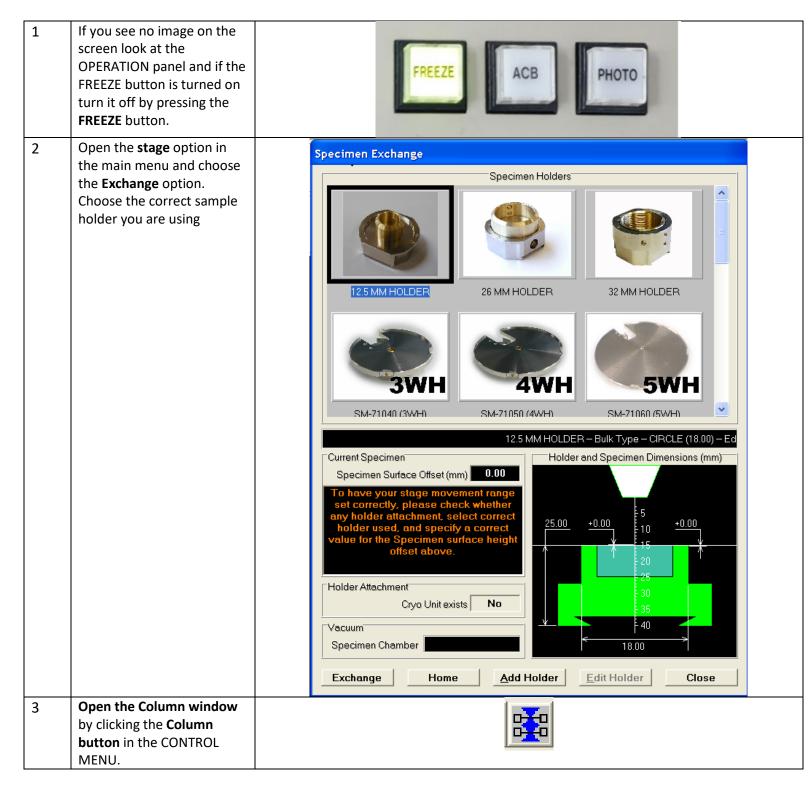




*** Operation panel



Sample Observation



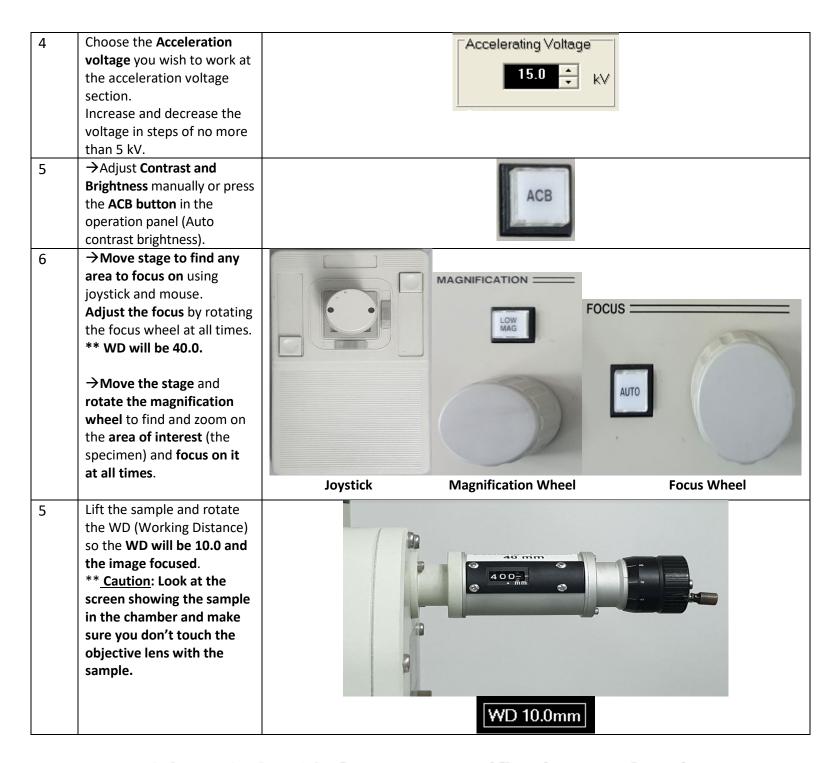


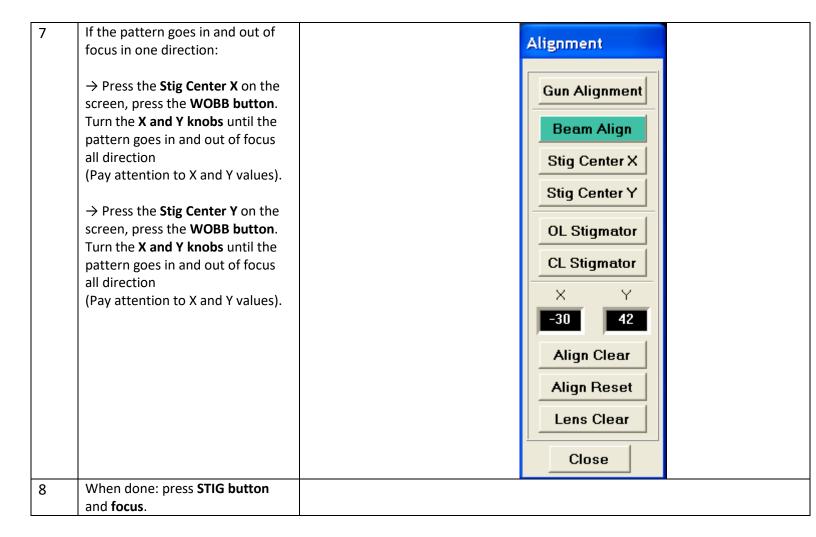
Table 3.3 Relationship between magnification, accelerating voltage, and working distance

Maximum magnification

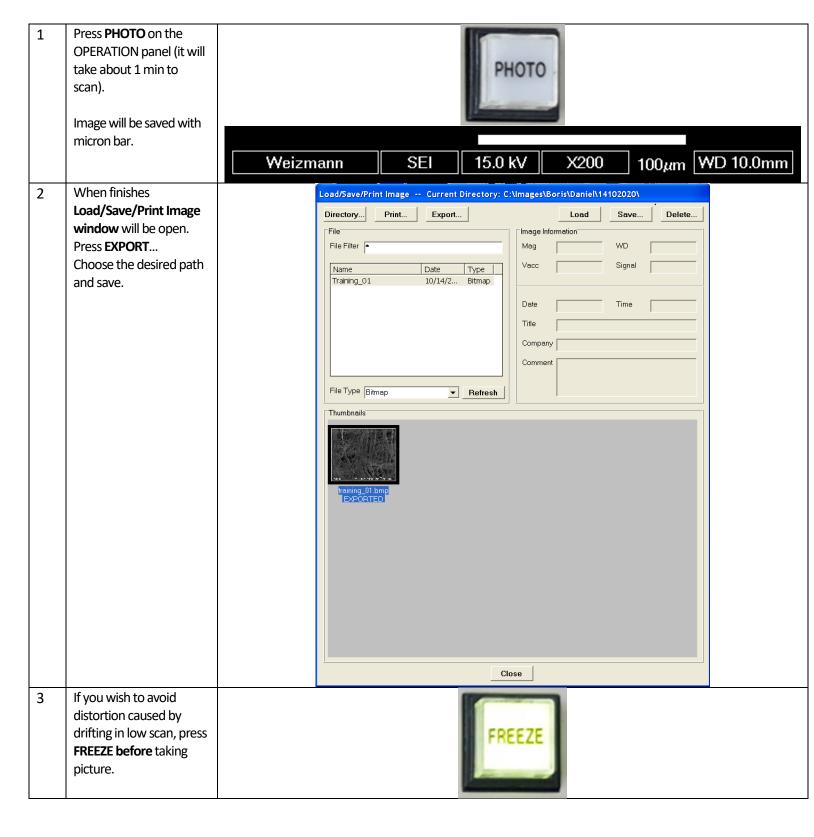
Accelerating voltage (kV)	WD (mm)						
	4	6	10	15	25	40	
0.5	150 K	140 K	120 K	110 K	90 K	70 K	
1	230 K	220 K	190 K	170 K	130 K	100 K	
2	350 K	330 K	270 K	230 K	180 K	140 K	
5	500 K	400 K	400 K	350 K	250 K	200 K	
10					450 K	350 K	250 K
15					400 K	300 K	
20		500 K	500 K	500 K	450 K	350 K	
25		5			300 K	500 K	370 K
30		AAA			300 K	400 K.	

Beam Alignment

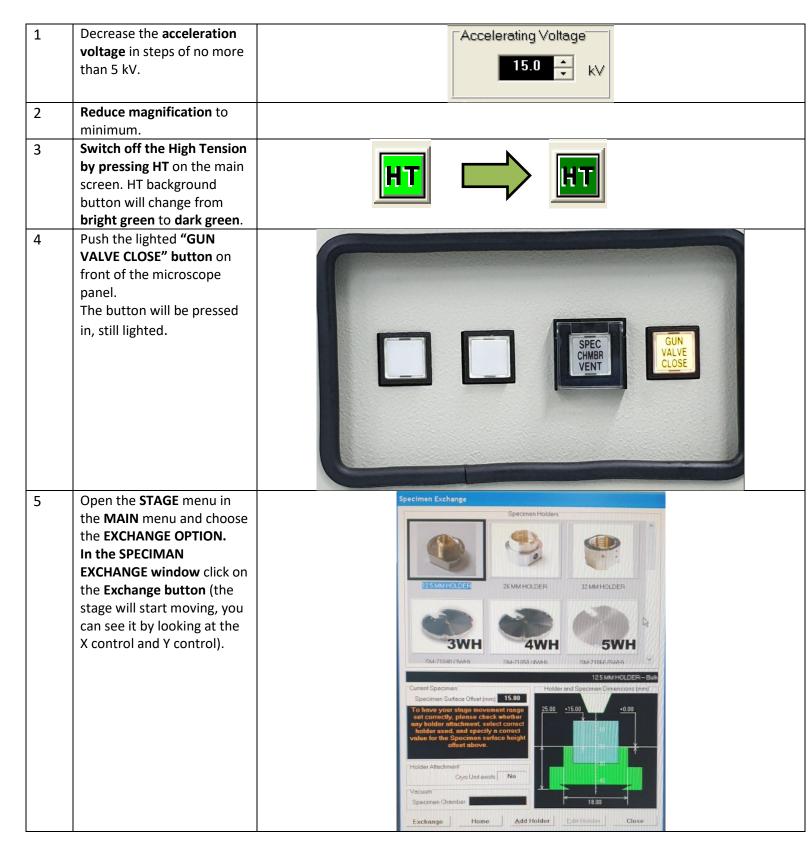
1	Make sure the image is the sharpest you can achieve.	
2	When STIG is on turn the X and Y knobs until the image is the sharpest you can achieve.	ALIGNMENT STIG ALIGN OFF
		X
3	If the image is moving while doing focus, do the wobb procedure (continue the next step).	
4	Focus a defined pattern (circle, square)	
5	Press the WOBB button.	ALIGNMENT STIG ALIGN OFF
6	Turn the X and Y knobs until the pattern goes in and out of focus all direction simultaneously and you get the minimum movement of the picture. (Pay attention to X and Y values before you start to rotate and follow it).	



Taking a picture



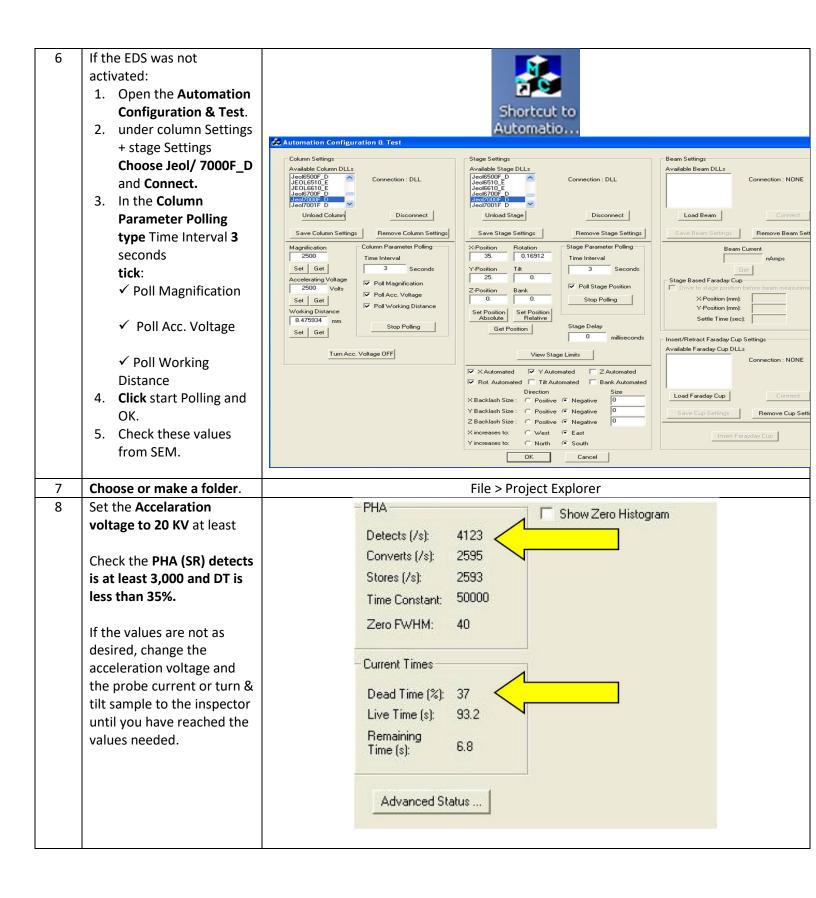
Sample removal



6	Set the WD control to 40.0 on the microscope body on the right side by turning the wheel. SET the stage tilt to 0.0.	40 mm
7	Make sure the EXCH POSN indication has turned on.	EXCHANGE CHAMBER VENT VENT STAGE HLDR
8	Pull the rod up swing it in 90 degrees carefully and smoothly slide the rod in completely. Look at the chamber internal camera and see that the sample is unloaded.	
9	Loosen the clip on the side of the exchange chamber. Press and hold the VENT button on side of the chamber until blinking.	VENT
10	When Vent button is lighted the chamber has vented. Open the door and remove the specimen holder .	
11	Close the exchange chamber and fasten the clip. Press and hold the EVAC button until blinking.	EVAC
12	DO NOT CLOSE THE JEOL SOFTWARE!	

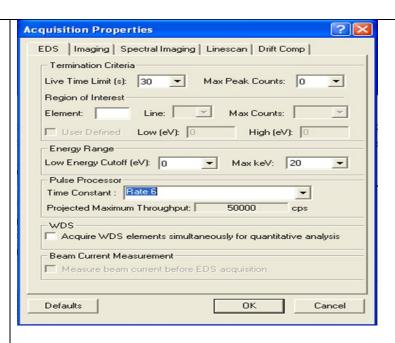
EDS SCAN

1	Insert the sample to the SEM and Zoom to the area you wish to diagnose (horizontally). Follow the instruction of sample mounting, sample observation and beam alignment with SEM.	
2	Place the sample at 10 mm Working distance.	WD 10.0mm
3	Turn off the Infrared Camera (infrared interferes with the measurements).	DEBEN 22
4	Transfer the control to the EDS computer by pressing on Button 2 on the KVM.	AAATTI SAATTI SA
5	Activate the EDS software (NSS) if it is not activated.	NSS NSS



9 Click Edit > Ecquisition
Properties > EDS.

Set the Live Time Limit
(detection time), Max
Peak Counts and Time
Constant (Rate 6).



In the Microanalysis panel choose the desired scan option and press the Acquire an averaged electron image icon to take a picture.

